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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. SERIAL NO. 108426-00015 10/081,151 APPLICANT

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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FILING DATE	GROUP
February 25, 2002	2175

## **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
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EXAMINER - Mellussa M Chosnack	BILGOY
*EXAMINER: Initial if reference considered, whether or not citation is in	n conformance with MPEP 609; Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

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